

## Analysis of Reliability of A Two-Non-Identical Units Cold Standby Repairable System Has Two Types of Failure

Praveen Gupta<sup>1\*</sup> and Pooja Vinodiya<sup>2</sup>

School of Studies in Statistics, Vikram University, Ujjain (M.P.) – 456010

\*Corresponding Author: [poojavinodia10@gmail.com](mailto:poojavinodia10@gmail.com)

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**Abstract-** This paper shows the analysis of reliability of a system composed of the two- N.I.U.,  $N_O$  and  $N_S$  in which  $N_O$  is operative and  $N_S$  is kept in standby mode upon failure of operative units  $N_O$  units  $N_S$  become operative instantaneously. Unit-1 has two types of failures. Let failure time distribution of type 1 and type 2 are assumed to be exponential with parameters  $\lambda_1$  and  $\lambda_2$  respectively, and the repair time is taken as general. When the second unit is failed it goes for replacement.

**Keywords-** Reliability, MTSF, Availability, Busy period, Mean Sojourn Time

### 1.1 INTRODUCTION

Concentrate the unwavering quality of machine repair issue is critical in our life since it is broadly utilized in modern framework and assembling framework. Any framework ends up questionable because of different reasons. In the conventional frameworks, the units of the framework have just two states up and down. Be that as it may, much of the time the units of the framework can have limited number of states. Most unwavering quality models expect that the up and down times of the parts are exponentially conveyed.

Wei, L., et al (1998) presented stochastic investigation of a repairable framework with three units and two repair

3. The o - unit is non-repairable, hence upon failure it goes for replacement
4. A single repairman is always available.
5. The failure time distributions of both the units, and time of replacement are taken as exponential although the repair time is taken general.

### 1.3 STATES AND NOTATIONS

#### (a) Symbols for the states

$N_0^i \ i = 1, 2$  : Unit – i is in N – Mode and operative

$N_s^i \ i = 1, 2$  : Unit – i is in N – Mode and standby

facilities. Agarwal, S.C., et al (2010) presented Reliability characteristic of cold-standby redundant system. In some unwavering quality parameters of a three state repairable framework with ecological disappointment were assessed. El-Damcese, M.A. (1997) studied “Human error and common-cause failure modelling of a two-unit multiple system.

### 1.2 DESCRIPTION AND ASSUMPTIONS OF THE SYSTEM

1. The system contains two N. I. U.. Initially unit first is operative and second is standby.
2. Both units has two modes N and F-Mode.

$F_R^2$  : Unit – 2 is in F – Mode and under replacement

$F_{WR}^2$  : Unit – 2 is in F – Mode and waiting for replacement

$F_r^1$  : Unit – 1 is in F – Mode and under repair

$F_{2r}^1$  : Unit – 1 is in F – Mode and under repair

#### UP STATES

$S_0 = (N_o^1, N_s^2)$  ;  $S_{1=} (F_r^1, N_o^2)$

$$S_2 = (F_{2r}^1, N_o^2) ; S_5 = (N_o^1, F_R^2)$$

of first unit.

**DOWN STATES**

$$S_3 = (F_r^1, F_{WR}^2) ; S_4 = (F_{2r}^1, F_{WR}^2)$$

**NOTATIONS**

$\lambda_1$  : Type 1 of failure rate of first unit

$\lambda_2$  : Type 2 of failure rate

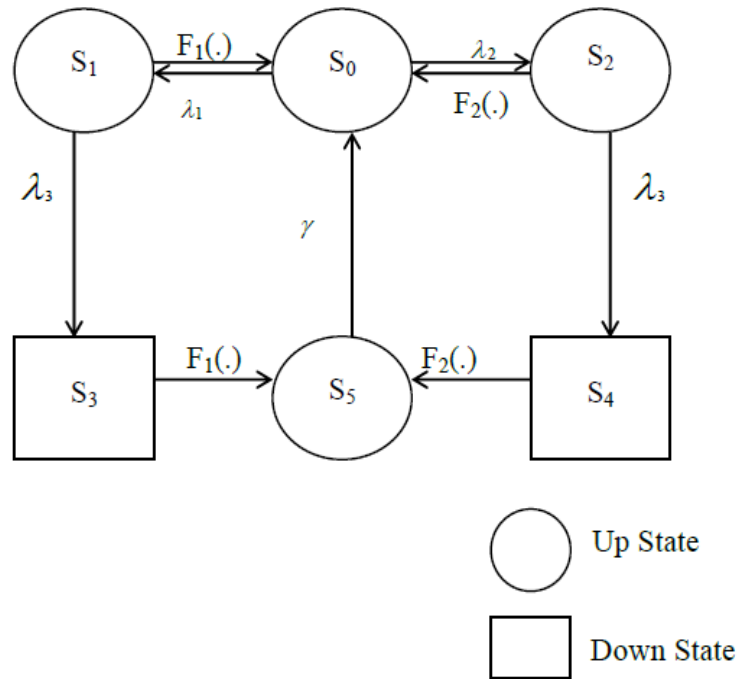
$F_1(.)$  : c.d.f. of repair time of type-1

$F_2(.)$  : c.d.f. of repair time of type-2

$\lambda_3$  : Constant failure rate of second unit

$\gamma$  : Replacement rate of second unit

**TRANSITION DIAGRAM:**



**Figure- 1.1 Shown States of the system with possible transitions**

#### 1.4 TRANSITION PROBABILITIES

As defined earlier,  $Q_{ij}(t)$  is the probability that the system transits from state  $S_i$  to  $S_j$  on or before time "t" or the c.d.f. of transition time from regenerative state  $S_i$  to  $S_j$ . So by the simple probabilistic arguments the transition probabilities if the system can be obtained as follows:

$$Q_{01}(t) = \int_0^t \lambda_1 e^{-\lambda_1 u} e^{-\lambda_2 u} du$$

$$= \frac{\lambda_1}{\lambda_1 + \lambda_2} \left[ 1 - e^{-(\lambda_1 + \lambda_2)t} \right]$$

$$Q_{35}(t) = \int_0^t dF_1(u)$$

$$Q_{45}(t) = \int_0^t dF_2(u)$$

#### 1.5 STEADY STATE TRANSITION PROBABILITIES

Let  $P_{ij}$  indicates the steady state transition probability of the system from state  $S_i$  to  $S_j$  ( $i, j = 1, 2, \dots, 5$ )

$$P_{01} = \frac{\lambda_1}{\lambda_1 + \lambda_2}, \quad P_{02} = \frac{\lambda_2}{\lambda_1 + \lambda_2},$$

$$P_{10} = \tilde{F}_1(\lambda_3), \quad P_{13} = 1 - \tilde{F}_1(\lambda_3),$$

$$P_{20} = \tilde{F}_2(\lambda_3), \quad P_{24} = 1 - \tilde{F}_2(\lambda_3),$$

$$P_{35} = 1, \quad P_{45} = 1,$$

$$Q_{02}(t) = \int_0^t \lambda_2 e^{-\lambda_1 u} e^{-\lambda_2 u} du$$

$$= \frac{\lambda_2}{\lambda_1 + \lambda_2} \left[ 1 - e^{-(\lambda_1 + \lambda_2)t} \right]$$

$$Q_{10}(t) = \int_0^t e^{-\lambda_3 u} dF_1(u)$$

$$Q_{13}(t) = \int_0^t \lambda_3 e^{-\lambda_3 u} \bar{F}_1(u) du$$

$$Q_{20}(t) = \int_0^t e^{-\lambda_3 u} dF_2(u)$$

$$Q_{24}(t) = \int_0^t \lambda_3 e^{-\lambda_3 u} \bar{F}_2(u) du$$

$$Q_{50}(t) = \int_0^t \gamma e^{-\gamma u} du$$

$$= \left[ 1 - e^{-\gamma t} \right].$$

$$P_{50} = 1.$$

The relations between probabilities

$$P_{01} + P_{02} = 1$$

$$P_{10} + P_{13} = 1$$

$$P_{20} + P_{24} = 1$$

$$P_{35} = 1$$

$$P_{45} = 1$$

$$P_{50} = 1$$

1.6 MEAN SOJOURN TIME

Mean time of stay in state  $S_i$  is called the mean sojourn time in state  $S_i$  and it is indicated by  $\psi_i$ . If  $T_i$  is the sojourn time in state  $S_i$ , then the mean sojourn time in state  $S_i$  is given by

$$\psi_i = \int P(T_i > t) dt$$

1.7 RELIABILITY AND MTSF

The probability of system that it is operable up to epoch  $t$  when it starts from state  $S_i$  is denoted by  $R_i(t)$ . In order to obtain  $R_0(t)$ , we consider the following two contingencies.

1. The probability that System stays up in state  $S_0$  and not make any transformation to other state up to epoch  $t$  is given by

$$e^{-(\lambda_1 + \lambda_2)t} = Z_0(t)$$

2. The probability that the System enters to the state  $S_1$  from  $S_0$  amid  $(u, u + du)$ ,  $u \leq t$  and after that beginning from  $S_1$ , it stays up consistently amid residual time  $(t-u)$ , is given by

$$\int_0^t q_{01}(u) du R_1(t-u) = q_{01} \odot R_1(t)$$

Then

$$\begin{aligned} R_0(t) &= Z_0(t) + q_{01}(t) \odot R_1(t) + q_{02}(t) \odot R_2(t) \\ R_1(t) &= Z_1(t) + q_{10}(t) \odot R_0(t) \\ R_2(t) &= Z_2(t) + q_{20}(t) \odot R_0(t) \end{aligned} \quad (1-3)$$

where

$$\begin{aligned} Z_0 &= e^{-(\lambda_1 + \lambda_2)t} & Z_1 &= e^{-\lambda_3 t} \overline{F}_1(t) \\ Z_2 &= e^{-\lambda_3 t} \overline{F}_2(t) \end{aligned}$$

$$\begin{aligned} \psi_0 &= \frac{1}{\lambda_1 + \lambda_2} \\ \psi_1 &= \int_0^t e^{-\lambda_3 u} F_1(t) dt \\ \psi_2 &= \int_0^t e^{-\lambda_3 u} F_2(t) dt \\ \psi_3 &= \int_0^t \overline{F}_1(t) dt & \psi_4 &= \int_0^t \overline{F}_2(t) dt \\ \psi_5 &= \frac{1}{\gamma} \end{aligned}$$

Taking Laplace transforms of the above equations

$$\begin{aligned} R_0^*(s) &= Z_0^*(s) + q_{01}^*(s) \odot R_1^*(s) + q_{02}^*(s) \odot R_2^*(s) \\ R_1^*(s) &= Z_1^*(s) + q_{10}^*(s) \odot R_0^*(s) \\ R_2^*(s) &= Z_2^*(s) + q_{20}^*(s) \odot R_0^*(s) \end{aligned} \quad (4-6)$$

For briefness, We require mislaid argument 's' from  $q_{ij}^*(s)$ ,  $Z_i^*(s)$  and  $R_i^*(s)$ . Solving the above matrix equation for  $R_0^*(s)$ , we get

$$R_0^*(s) = \frac{N_1(s)}{D_1(s)} \quad (7)$$

where

$$\begin{aligned} N_2(s) &= Z_0^* + q_{01}^* Z_1^* + q_{20}^* Z_2^* \\ D_2(s) &= 1 - q_{01}^* q_{10}^* + q_{02}^* q_{20}^* \end{aligned}$$

Reliability of the system can be obtained by taking the inverse Laplace transform of equation (7).

Formula for MTSF

$$\begin{aligned} E(T_0) &= \int R_0(t) dt \\ &= \lim_{s \rightarrow 0} R_0^*(s) \\ &= \frac{N_1(0)}{D_1(0)} \end{aligned} \quad (1-8)$$

To determine the  $N_1(0)$  and  $D_1(0)$ , we first obtain  $Z_i^*(0)$  by using the following result

$$\lim_{s \rightarrow 0} Z_i^*(s) = \int Z_i(t) dt$$

Therefore,

$$Z_0^*(0) = \psi_0 \text{ and } Z_i^*(0) = \psi_i \quad (i = 0, 1, 2, 3, 4, 5)$$

Thus using  $q_{ij}^*(0) = p_{ij}$  we get  $N_1(0)$  and  $D_1(0)$ .

We can get the MTSF of the system by putting these values of  $N_1(0)$  and  $D_1(0)$  in (8).

### 1.8 AVAILABILITY ANALYSIS

#### 1. When unit is in normal (N) mode and operative

Let  $A_i^N(t)$  be the probability that starting from state  $S_i$  the system is up, due to a unit in N-mode at epoch  $t$ . By using similar probabilistic arguments as in earlier situation, one can easily obtain the following recurrence relations:

$$A_0^N(t) = Z_0(t) + q_{01}(t) \odot A_1^N(t) + q_{02}(t) \odot A_2^N(t)$$

$$A_1^N(t) = Z_1(t) + q_{10}(t) \odot A_0^N(t) + q_{15}^{(2)}(t) \odot A_5^N(t)$$

$$A_2^N(t) = Z_2(t) + q_{20}(t) \odot A_0^N(t) + q_{25}^{(4)}(t) \odot A_5^N(t)$$

$$A_3^N(t) = q_{35}(t) \odot A_5^N(t)$$

$$A_4^N(t) = q_{45}(t) \odot A_5^N(t)$$

$$A_5^N(t) = Z_5 + q_{50}(t) \odot A_0^N(t)$$

After taking Laplace Transformation and Solving these equation for  $A_0^{N*}(s)$

We get

$$A_0^{N*}(s) = \frac{N_2(s)}{D_2(s)}$$

where

$$N_2(s) = \frac{Z_0^* + q_{01}^* Z_1^* + q_{01}^* q_{15}^* Z_5^* + q_{02}^* Z_2^* + q_{02}^* q_{25}^* Z_5^*}{Z_5^*}$$

$$D_2(s) = 1 - q_{01}^* q_{10}^* - q_{02}^* q_{20}^* - (q_{01}^* q_{15}^* + q_{02}^* q_{25}^*) q_{50}^*$$

Therefore, the steady state availability is given by

$$A_0^N = \lim_{t \rightarrow \infty} A_0^N(t)$$

$$\lim_{s \rightarrow 0} S A_0^{*N}(s)$$

$$\lim_{s \rightarrow 0} S \frac{N_2(s)}{D_2(s)}$$

So by the following results

$$Z_i^*(0) = \int Z_i(t) dt = \psi_i$$

and  $q_{ij}^*(0) = p_{ij}$ , we have

$$D_2(0) = 0.$$

### 1.9 BUSY PERIOD ANALYSIS

#### 1. When repairman is occupied in the repair of failed unit

Let  $B_i^F(t)$  be the likelihood that the repairman occupied in fixing the failed unit.  $B_0^F(t) = q_{01}(t) \odot B_1^F(t) + q_{02}(t) \odot B_2^F(t)$

$$B_1^F(t) = Z_1(t) + q_{10}(t) \odot B_0^F(t) + q_{15}^{(2)}(t) \odot B_5^F(t)$$

$$B_2^F(t) = Z_2(t) + q_{20}(t) \odot B_0^F(t) + q_{25}^{(4)}(t) \odot B_5^F(t)$$

$$B_3^F(t) = Z_3(t) + q_{35}(t) \odot B_5^F(t)$$

$$B_4^F(t) = Z_4(t) + q_{45}(t) \odot B_5^F(t)$$

$$B_5^F(t) = q_{50}(t) \odot B_0^F(t)$$

After taking Laplace Transformation and solving for  $B_0^{F*}(s)$

$$B_0^{F*}(s) = \frac{N_3(s)}{D_2(s)}$$

$$N_3(s) = Z_2^* q_{01}^* (q_{35}^* + q_{50}^*) + Z_1^* q_{25}^* q_{45}^* (1 - q_{50}^* q_{01}^*) + Z_3^* q_{01}^* (q_{10}^* + q_{15}^* q_{35}^*)$$

$$D_2(s) = 1 - q_{01}^* q_{10}^* - q_{02}^* q_{20}^* - (q_{01}^* q_{15}^* + q_{02}^* q_{25}^*) q_{50}^*$$

**2. When repairman is occupied in replacement of a failed unit**

Let  $B_i^R(t)$  be the probability that starting from state  $S_i$ , the repairman is occupied in the replacement of a failed unit.

$$B_0^R(t) = q_{01}(t) \odot B_1^R(t) + q_{02}(t) \odot B_2^R(t)$$

$$B_1^R(t) = q_{10}(t) \odot B_0^R(t) + q_{15}^{(2)}(t) \odot B_5^R(t)$$

$$B_2^R(t) = q_{20}(t) \odot B_0^R(t) + q_{25}^{(4)}(t) \odot B_5^R(t)$$

$$B_3^R(t) = q_{35}(t) \odot B_5^R(t)$$

$$B_4^R(t) = q_{45}(t) \odot B_5^R(t)$$

$$B_5^R(t) = Z_5(t) + q_{50}(t) \odot B_0^R(t)$$

After taking Laplace Transformation and solving for  $B_0^{F*}(s)$  we get

$$B_0^{F*}(s) = \frac{N_4(s)}{D_2(s)}$$

$$N_4(s) = q_{25}^* q_{45}^* (1 - q_{50}^* q_{01}^*) + q_{01}^* (q_{10}^* + q_{15}^* q_{35}^*) Z_5^*$$

$$D_2(s) = 1 - q_{01}^* q_{10}^* - q_{02}^* q_{20}^* - (q_{01}^* q_{15}^* + q_{02}^* q_{25}^*) q_{50}^*$$

**1.10 CONCLUSION**

This model was constructed for a repairable system with two N. I. U.. Availability, reliability, MTSF and also find difference between type-1 and type-2 failure the result were shown graphically. Result indicates that the MTSF and the system reliability depend on the failure rate.

**1.11 PARTICULAR CASE**

We consider the condition when all the repair times are follows exponential distribution i.e.

$$F_1(t) = 1 - e^{-\theta_1} \quad F_2(t) = 1 - e^{-\theta_2}$$

Then

$$p_{10} = \frac{\theta_1}{\theta_1 + \lambda_3} \quad p_{13} = \frac{\lambda_3}{\theta_1 + \lambda_3}$$

$$p_{20} = \frac{\theta_2}{\theta_2 + \lambda_3} \quad p_{24} = \frac{\lambda_3}{\theta_2 + \lambda_3}$$

$$p_{57} = \frac{\beta}{\theta + \beta} \quad p_{50} = \frac{\theta}{\theta + \beta} \quad \psi_1 = \frac{1}{\lambda_3 + \theta_1}$$

$$\psi_2 = \frac{1}{\lambda_3 + \theta_2} \quad (34-39)$$

$$\psi_3 = \frac{1}{\theta_1} \quad \psi_4 = \frac{1}{\theta_2}$$

**1.12 GRAPHICAL STUDY**

In graphical study we can see the behaviour of the system, for this curves are plotted for MTSF at the different values of  $\lambda_1$  and  $\lambda_2$  and kept other parameter at fixed value.

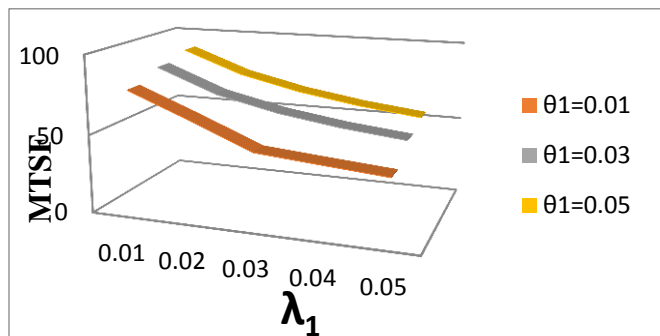


Figure 4.2 shown MTSF w.r.t. type 1 failure.

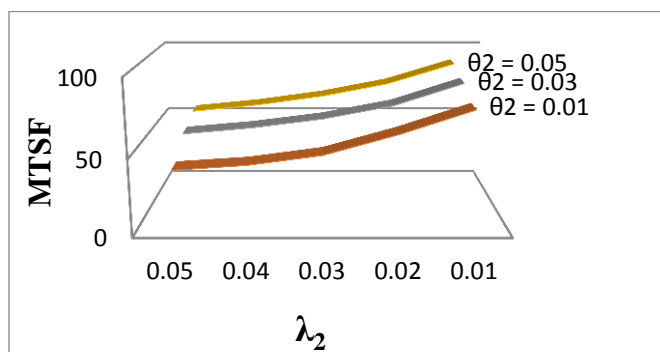


Figure 4.3 shown MTSF w.r.t. type 2 failure.

#### Author Profile

*Ms. Pooja Vinodiya* pursued Bachelor of Science from G.D.C. College, Ujjain in 2010 and Master of Science from SOS in Statistics, Vikram University (Gold Medalist) in year 2012. She is currently pursuing Ph.D. and awarded JRF with Rajeev Gandhi National Fellowship, UGC (New Delhi) in year 2014. She is published two research papers in reputed international journals and conference including ISSAC-2016 at Aligarh Muslim University and National Conference at Savitribai Phule Pune University. Her main research work focus on Reliability Analysis, Availability Analysis, Preventive Maintenance of system. She has five years research experience.



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